

SLOVENSKI STANDARD

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dcgfYXcj UbY[UglghYa U!" "XY. DfYg_i ýYj UbUgdYW]_UWUÜcXj]gbUcX'dfc]U
fDGHGtžnUZ_gbc 'fUX]g_c'nU_`1 JhYj 'fI HÉ

Digital Enhanced Cordless Telecommunications (DECT); Integrated Services Digital Network (ISDN); DECT/ISDN interworking for intermediate system configuration; Part 3: Profile Specific Test Specification (PSTS) for Fixed radio Termination (FT)

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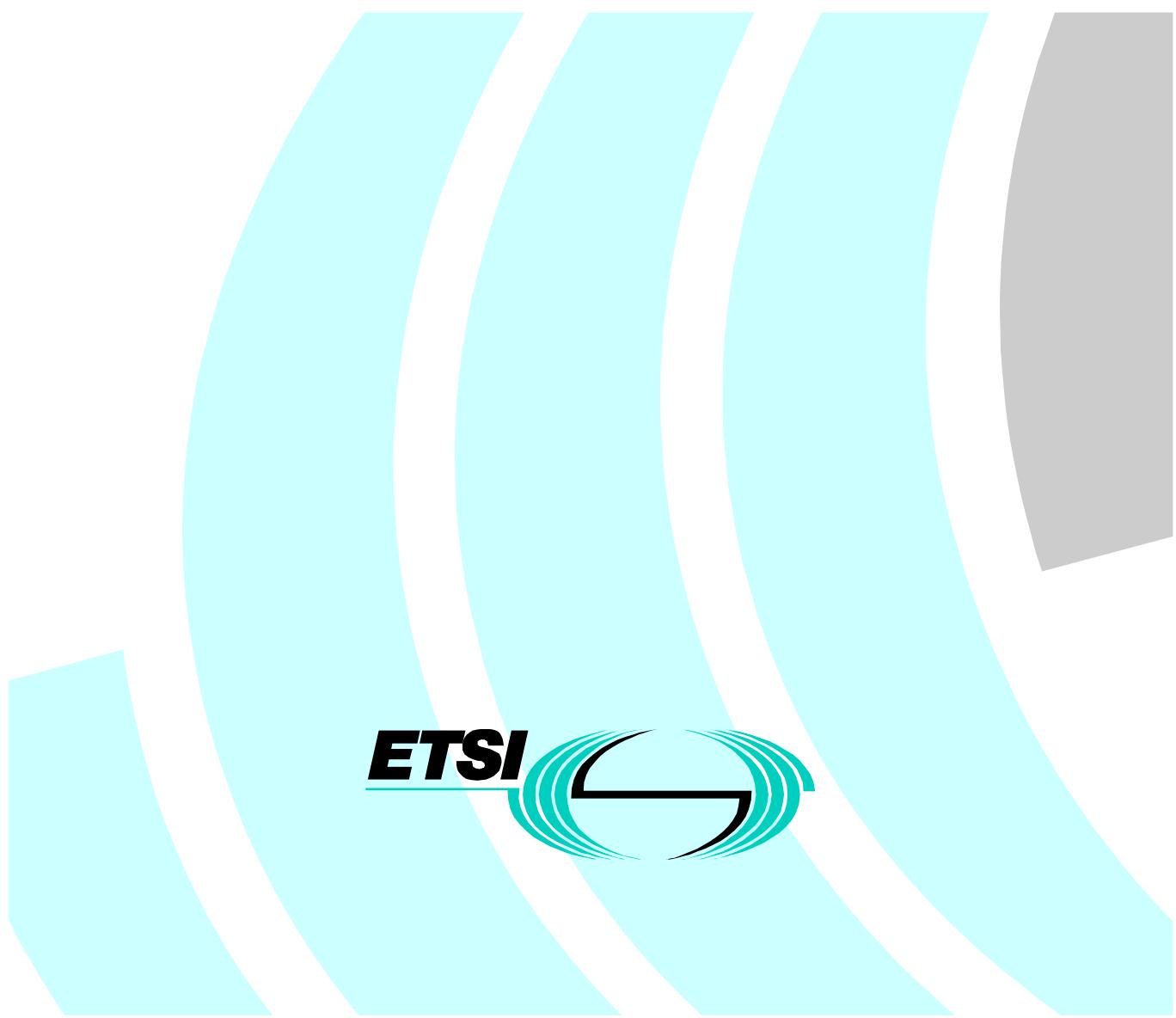
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